



CERTIFICATE OF ACCREDITATION

ANSI National Accreditation Board
11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

Transcat-Phoenix
8240 S. Kyrene Road, Suite 107
Tempe, AZ 85284

has been assessed by ANAB and meets the requirements of international standard

ISO/IEC 17025:2017

and national standards

ANSI/NCSL Z540-1-1994 (R2002)

while demonstrating technical competence in the field of

CALIBRATION

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AC-2489.11

Certificate Number


ANAB Approval

Certificate Valid Through: 09/07/2021
Version No. 004 Issued: 09/04/2019



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND
ANSI/NCSL Z540-1-1994 (R2002)

Transcat – Phoenix
8240 S. Kyrene Road, Suite 107
Tempe, AZ 85284
Ryan Verdin

CALIBRATION

Valid to: **September 7, 2021**

Certificate Number: **AC-2489.11**

Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Sine Wave Flatness ¹ (0.3 V to 1 V, 50 Ω)	10 Hz to 1 MHz	0.073 %	Agilent 11050A
	1 MHz to 10 MHz	0.14 %	
	10 MHz to 30 MHz	0.39 %	
	30 MHz to 50 MHz	0.79 %	
	50 MHz to 80 MHz	1.6 %	
	80 MHz to 100 MHz	2.4 %	
(1 V to 3 V, 50 Ω)	10 Hz to 1 MHz	0.071 %	Agilent 11049A
	1 MHz to 10 MHz	0.11 %	
	10 MHz to 30 MHz	0.21 %	
	30 MHz to 50 MHz	0.47 %	
	50 MHz to 80 MHz	0.96 %	
	80 MHz to 100 MHz	1.3 %	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Current – Measuring Equipment ¹	0 μA to 220 μA		Fluke 5720A
	10 Hz to 20 Hz	0.032 % + 16 nA	
	20 Hz to 40 Hz	0.019 % + 10 nA	
	40 Hz to 1 kHz	0.014 % + 8 nA	
	1 kHz to 5 kHz	0.029 % + 12 nA	
	5 kHz to 10 kHz	0.11 % + 65 nA	
	0.22 mA to 2.2 mA		
	10 Hz to 20 Hz	0.032 % + 40 nA	
	20 Hz to 40 Hz	0.019 % + 35 nA	
	40 Hz to 1 kHz	0.014 % + 35 nA	
	1 kHz to 5 kHz	0.021 % + 110 nA	
	5 kHz to 10 kHz	0.11 % + 650 nA	
	2.2 mA to 22 mA		
	10 Hz to 20 Hz	0.032 % + 0.4 μA	
	20 Hz to 40 Hz	0.019 % + 0.35 μA	
	40 Hz to 1 kHz	0.015 % + 0.35 μA	
	1 kHz to 5 kHz	0.022 % + 0.55 μA	
	5 kHz to 10 kHz	0.11 % + 5 μA	
	22 mA to 220 mA		
	10 Hz to 20 Hz	0.032 % + 4 μA	
20 Hz to 40 Hz	0.018 % + 3.5 μA		
40 Hz to 1 kHz	0.013 % + 2.5 μA		

Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment	
AC Current – Measuring Equipment ¹	1 kHz to 5 kHz	0.021 % + 3.5 μA	Fluke 5720A	
	5 kHz to 10 kHz	0.11 % + 10 μA		
	0.22 A to 2.2 A			
	20 Hz to 1 kHz	0.027 % + 35 μA		
	1 kHz to 5 kHz	0.045 % + 80 μA		
		5 kHz to 10 kHz	0.70 % + 160 μA	Fluke 5720A with 5725A
	2.2 A to 11 A			
		5 kHz to 10 kHz	0.36 % + 0.75 mA	
		2.2 A to 20 A		Fluke Y5020 with Agilent 3458A opt 2
		45 Hz to 100 Hz	0.021 % + 230 μA	
	100 Hz to 300 Hz	0.024 % + 230 μA		
	300 Hz to 1 kHz	0.033 % + 230 μA		
	1 kHz to 3 kHz	0.061 % + 230 μA		
	3 kHz to 4 kHz	0.075 % + 230 μA		
	4 kHz to 5 kHz	0.088 % + 230 μA		
Extended Frequency Ranges ¹	29 μA to 330 μA		Fluke 5520A	
	10 kHz to 30 kHz	1.2 % + 0.31 μA		
	330 μA to 3.3 mA			
	10 kHz to 30 kHz	0.78 % + 0.47 μA		
	3.3 mA to 33 mA		Fluke 5520A	
	10 kHz to 30 kHz	0.31 % + 3.1 μA		



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment	
Extended Frequency Ranges ¹	33 mA to 330 mA	0.31 % + 0.16 mA	Fluke 5520A	
	10 kHz to 30 kHz			
Clamp-on Ammeter Toroidal Type ¹ Transformer Type	20 A to 150 A	0.35 % + 30 mA	Fluke 5520A with 5500A/Coil	
	45 Hz to 65 Hz			
	65 Hz to 440 Hz	0.94 % + 50 mA		
	150 A to 1000 A	0.34 % + 0.13 A		
45 Hz to 65 Hz	1.2 % + 0.23 A			
65 Hz to 440 Hz				
Clamp-on Ammeter Non-Toroidal Type ¹ Hall Effect Sensor	20 A to 150 A	0.68 % + 0.29 A	Fluke 5520A with 5500A/Coil	
	45 Hz to 65 Hz			
	65 Hz to 440 Hz			1.2 % + 0.29 A
	150 A to 1 000 A	0.66 % + 1 A		
	45 Hz to 65 Hz			1.4 % + 1.1 A
	65 Hz to 440 Hz			
AC Current – Measure ¹	0 μA to 100 μA	0.46 % + 35 nA	Agilent 3458A opt 2	
	10 Hz to 20 Hz			
	20 Hz to 45 Hz			0.18 % + 35 nA
	45 Hz to 100 Hz			0.072 % + 35 nA
	100 Hz to 5 kHz	0.072 % + 35 nA		
	100 μA to 1 mA	0.46 % + 0.23 μA		
	10 Hz to 20 Hz			0.17 % + 0.23 μA
	20 Hz to 45 Hz			



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Current – Measure ¹	45 Hz to 100 Hz	0.071 % + 0.23 μA	Agilent 3458A opt 2
	100 Hz to 5 kHz	0.038 % + 0.23 μA	
	1 mA to 10 mA		
	10 Hz to 20 Hz	0.46 % + 2.3 μA	
	20 Hz to 45 Hz	0.17 % + 2.3 μA	
	45 Hz to 100 Hz	0.071 % + 2.3 μA	
	100 Hz to 5 kHz	0.038 % + 2.3 μA	
	10 mA to 100 mA		
	10 Hz to 20 Hz	0.46 % + 23 μA	
	20 Hz to 45 Hz	0.17 % + 23 μA	
	45 Hz to 100 Hz	0.07 % + 23 μA	
	100 Hz to 5 kHz	0.037 % + 23 μA	
	100 mA to 1 A		
	10 Hz to 20 Hz	0.46 % + 0.23 mA	
	20 Hz to 45 Hz	0.19 % + 0.23 mA	
	45 Hz to 100 Hz	0.097 % + 0.23 mA	
	100 Hz to 5 kHz	0.12 % + 0.23 mA	
1 A to 20 A		Fluke Y5020 with Agilent 3458A opt 2	
50 Hz to 100 Hz	0.021 % + 230 μA		
100 Hz to 300 Hz	0.024 % + 230 μA		
300 Hz to 1 kHz	0.033 % + 230 μA		
	1 kHz to 3 kHz	0.061 % + 230 μA	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Current – Measure ¹	3 kHz to 4 kHz	0.075 % + 230 μA	Fluke Y5020 with Agilent 3458A opt 2
	4 kHz to 5 kHz	0.088 % + 230 μA	
DC Resistance – Measuring Equipment and Measure ¹	0 Ω to 10 Ω	18 μΩ/Ω + 58 μΩ	Agilent 3458A with Decade Resistor
	10 Ω to 100 Ω	15 μΩ/Ω + 0.58 mΩ	
	100 Ω to 1 kΩ	13 μΩ/Ω + 0.58 mΩ	
	1 kΩ to 10 kΩ	12 μΩ/Ω + 5.8 mΩ	
	10 kΩ to 100 kΩ	13 μΩ/Ω + 58 mΩ	
	100 kΩ to 1 MΩ	21 μΩ/Ω + 2.3 Ω	
	1 MΩ to 10 MΩ	62 μΩ/Ω + 0.12 kΩ	Extended Arm Bridge
	10 MΩ to 100 MΩ	0.012 % + 0.28 kΩ	
	100 MΩ to 1 GΩ	0.012 % + 9.7 kΩ	
	1 GΩ to 10 GΩ	0.012 % + 0.42 MΩ	
	10 GΩ to 100 GΩ	0.012 % + 45 MΩ	
	100 GΩ to 300 GΩ	0.016 % + 45 MΩ	
	300 GΩ to 700 GΩ	0.016 % + 0.11 GΩ	
	700 GΩ to 1 TΩ	0.016 % + 0.49 GΩ	
DC Resistance – Measuring Equipment ¹	10 μΩ	0.4 %	Fixed Resistor
	100 μΩ	0.046 %	
	1 mΩ	0.046 %	
	10 mΩ	35 μΩ/Ω	
	100 mΩ	67 μΩ/Ω	
	1 Ω	96 μΩ/Ω	Fluke 5720A



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
DC Resistance – Measuring Equipment ¹	1.9 Ω	96 μΩ/Ω	Fluke 5720A
	10 Ω	24 μΩ/Ω	
	19 Ω	24 μΩ/Ω	
	100 Ω	11 μΩ/Ω	
	190 Ω	11 μΩ/Ω	
	1 kΩ	10 μΩ/Ω	
	1.9 kΩ	10 μΩ/Ω	
	10 kΩ	10 μΩ/Ω	
	19 kΩ	12 μΩ/Ω	
	100 kΩ	11 μΩ/Ω	
	190 kΩ	13 μΩ/Ω	
	1 MΩ	23 μΩ/Ω	
	1.9 MΩ	21 μΩ/Ω	
	10 MΩ	42 μΩ/Ω	
	19 MΩ	49 μΩ/Ω	
100 MΩ	120 μΩ/Ω		
DC Current – Measuring Equipment and Measure ¹	0 μA to 100 μA	26 μA/A + 0.92 nA	Agilent 3458A with Current Source
	100 μA to 1 mA	26 μA/A + 5.8 nA	
	1 mA to 10 mA	26 μA/A + 58 nA	
	10 mA to 100 mA	41 μA/A + 0.58 μA	
	100 mA to 1 A	130 μA/A + 12 μA	
	1 A to 20 A	37 μA/A	Fluke Y5020 with Agilent 3458A opt 2



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
DC Current – Measure	20 A to 100 A	0.046 %	L & N 4361 with Agilent 3458A opt 2
Clamp-on Ammeter Non-Toroidal Type ¹ Hall Effect Sensor	20 A to 150 A	0.53 % + 0.17 A	Fluke 5520A with 5500A/Coil
	150 A to 1000 A	0.52 % + 0.58 A	
DC Voltage – Measuring Equipment ¹	0 mV to 220 mV	9.6 μV/V + 0.4 μV	Fluke 5720A
	220 mV to 2.2 V	5.6 μV/V + 0.7 μV	
	2.2 V to 11 V	4.1 μV/V + 2.5 μV	
	11 V to 22 V	4.1 μV/V + 4 μV	
	22 V to 220 V	5.9 μV/V + 40 μV	
	220 V to 1100 V	7.6 μV/V + 0.40 mV	Fluke 5720A w/5725A
DC Voltage – Measure	0 mV to 100 mV	8.3 μV/V + 0.35 μV	Agilent 3458A opt 2
	100 mV to 10 V	5.3 μV/V + 0.35 μV	
	10 V to 100 V	7.6 μV/V + 35 μV	
	100 V to 500 V	11 μV/V + 120 μV	
	500 V to 700 V	14 μV/V + 120 μV	
	700 V to 1000 V	21 μV/V + 120 μV	
	1 kV to 10 kV	0.042 % + 0.092 V	Vitretek 4700A
	10 kV to 35 kV	0.047 % + 2.4 V	Vitretek 4700A/HVL-35
	35 kV to 50 kV	0.056 % + 2.4 V	Vitretek 4700A/HVL-70
	50 kV to 70 kV	0.088 % + 2.4 V	Vitretek 4700A/HVL-70
	70 kV to 100 kV	0.17 % + 2.5 V	Vitretek 4700A/HVL-100



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC High Voltage – Measure ¹	700 V to 5 kV		Vitrek 4700A with HVL Series Probe
	0.01 Hz to 10 Hz	0.15 % + 0.17 V	
	10 Hz to 30 Hz	0.13 % + 0.29 V	
	30 Hz to 200 Hz	0.11 % + 0.37 V	
	200 Hz to 450 Hz	0.48% + 0.17 V	
	450 Hz to 600 Hz	0.88% + 0.17 V	
	5 kV to 30 kV		Vitrek 4700A with HVL Series Probe
	0.01 Hz to 10 Hz	0.20 % + 2.4 V	
	10 Hz to 30 Hz	0.15 % + 2.4 V	
	30 Hz to 200 Hz	0.12% + 2.4 v	
	200 Hz to 450 Hz	0.71 % + 2.4 V	
	450 Hz to 600 Hz	1.4% + 2.4 V	
30 kV to 50 kV		Vitrek 4700A with HVL Series Probe	
0.01 Hz to 10 Hz	0.25 % + 2.5 V		
10 Hz to 30 Hz	0.19% + 2.5 V		
30 Hz to 70 Hz	0.14% + 2.5 V		
70 Hz to 200 Hz	0.70% + 2.5 V		
200 Hz to 450 Hz	2.9% + 2.5 V		
50 kV to 70 kV		Vitrek 4700A with HVL Series Probe	
0.01 Hz to 10 Hz	0.37% + 2.6 V		
10 Hz to 30 Hz	0.27 % + 2.6 V		
30 Hz to 70 Hz	0.18 % + 2.6 V		
70 Hz to 200 Hz	1.2% + 2.6V		
200 Hz to 450 Hz	1.7% + 2.6V		
AC Voltage – Measure ¹	0 mV to 10 mV		Agilent 3458A opt 2
	1 Hz to 40 Hz	0.039 % + 3.5 μV	
	40 Hz to 1 kHz	0.028 % + 1.3 μV	
	1 kHz to 20 kHz	0.038 % + 1.3 μV	
	20 kHz to 50 kHz	0.12 % + 1.3 μV	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Voltage – Measure ¹	50 kHz to 100 kHz	0.59 % + 1.3 μV	Agilent 3458A opt 2
	100 kHz to 300 kHz	4.6 % + 2.3 μV	
	10 mV to 100 mV		
	1 Hz to 40 Hz	0.013 % + 4.6 μV	
	40 Hz to 1 kHz	0.0094 % + 2.3 μV	
	1 kHz to 20 kHz	0.017 % + 2.3 μV	
	20 kHz to 50 kHz	0.035 % + 2.3 μV	
	50 kHz to 100 kHz	0.093 % + 2.3 μV	
	100 kHz to 300 kHz	0.36 % + 12 μV	
	300 kHz to 1 MHz	1.2 % + 12 μV	
	1 MHz to 2 MHz	1.8 % + 12 μV	
	100 mV to 1 V		
	1 Hz to 40 Hz	0.009 8 % + 46 μV	
	40 Hz to 1 kHz	0.009 4 % + 23 μV	
	1 kHz to 20 kHz	0.017 % + 23 μV	
	20 kHz to 50 kHz	0.036 % + 23 μV	
	50 kHz to 100 kHz	0.093 % + 23 μV	
	100 kHz to 300 kHz	0.35 % + 120 μV	
	300 kHz to 1 MHz	1.2 % + 120 μV	
	1 MHz to 2 MHz	1.8% + 120 μV	
1 V to 10 V			
1 Hz to 40 Hz	0.009 5 % + 0.46 mV		



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Voltage – Measure ¹	40 Hz to 1 kHz	0.009 5 % + 0.23 mV	Agilent 3458A opt 2
	1 kHz to 20 kHz	0.017 % + 0.23 mV	
	20 kHz to 50 kHz	0.036 % + 0.23 mV	
	50 kHz to 100 kHz	0.093 % + 0.23 mV	
	100 kHz to 300 kHz	0.35 % + 1.2 mV	
	300 kHz to 1 MHz	1.2 % + 1.2 mV	
	1 MHz to 2 MHz	1.7 % + 1.2 mV	
	10 V to 100 V		
	1 Hz to 40 Hz	0.024 % + 4.6 mV	
	40 Hz to 1 kHz	0.024 % + 2.3 mV	
	1 kHz to 20 kHz	0.024 % + 2.3 mV	
	20 kHz to 50 kHz	0.041 % + 2.3 mV	
	50 kHz to 100 kHz	0.14 % + 2.3 mV	
	100 kHz to 300 kHz	0.47 % + 12 mV	
	300 kHz to 1 MHz	1.7 % + 12 mV	
	100 V to 700 V		
	1 Hz to 40 Hz	0.047 % + 46 mV	
	40 Hz to 1 kHz	0.047 % + 23 mV	
	1 kHz to 20 kHz	0.071 % + 23 mV	
	20 kHz to 50 kHz	0.14 % + 23 mV	
	50 kHz to 100 kHz	0.35 % + 23 mV	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Voltage – Measuring Equipment ¹	0 mV to 2.2 mV		Fluke 5720A
	10 Hz to 20 Hz	0.1 % + 4 μV	
	20 Hz to 40 Hz	0.077 % + 4 μV	
	40 Hz to 20 kHz	0.077 % + 4 μV	
	20 kHz to 50 kHz	0.077 % + 4 μV	
	50 kHz to 100 kHz	0.13 % + 5 μV	
	100 kHz to 300 kHz	0.24 % + 10 μV	
	300 kHz to 500 kHz	0.34 % + 20 μV	
	500 kHz to 1 MHz	0.52 % + 20 μV	
	2.2 mV to 22 mV		
	10 Hz to 20 Hz	0.041 % + 4 μV	
	20 Hz to 40 Hz	0.028 % + 4 μV	
	40 Hz to 20 kHz	0.015 % + 4 μV	
	20 kHz to 50 kHz	0.026 % + 4 μV	
	50 kHz to 100 kHz	0.056 % + 5 μV	
	100 kHz to 300 kHz	0.11 % + 10 μV	
	300 kHz to 500 kHz	0.15 % + 20 μV	
	500 kHz to 1 MHz	0.28 % + 20 μV	
	22 mV to 220 mV		
	10 Hz to 20 Hz	0.025 % + 12 μV	
	20 Hz to 40 Hz	0.009 6 % + 7 μV	
	40 Hz to 20 kHz	0.008 6 % + 7 μV	



Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Voltage – Measuring Equipment ¹	20 kHz to 50 kHz	0.02 % + 7 μV	Fluke 5720A
	50 kHz to 100 kHz	0.046 % + 17 μV	
	100 kHz to 300 kHz	0.091 % + 20 μV	
	300 kHz to 500 kHz	0.14 % + 25 μV	
	500 kHz to 1 MHz	0.27 % + 45 μV	
	220 mV to 2.2 V		
	10 Hz to 20 Hz	0.024 % + 40 μV	
	20 Hz to 40 Hz	0.009 2 % + 15 μV	
	40 Hz to 20 kHz	0.004 8 % + 8 μV	
	20 kHz to 50 kHz	0.007 7 % + 10 μV	
	50 kHz to 100 kHz	0.011 % + 30 μV	
	100 kHz to 300 kHz	0.042 % + 80 μV	
	300 kHz to 500 kHz	0.1 % + 200 μV	
	500 kHz to 1 MHz	0.17 % + 300 μV	
	2.2 V to 22 V		
	10 Hz to 20 Hz	0.024 % + 0.4 mV	
	20 Hz to 40 Hz	0.009 2 % + 0.15 mV	
	40 Hz to 20 kHz	0.004 9 % + 0.05 mV	
	20 kHz to 50 kHz	0.007 8 % + 0.1 mV	
	50 kHz to 100 kHz	0.011 % + 0.2 mV	
	100 kHz to 300 kHz	0.028 % + 0.6 mV	
300 kHz to 500 kHz	0.1 % + 2 mV		



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Voltage – Measuring Equipment ¹	500 kHz to 1 MHz	0.15 % + 3.2 mV	Fluke 5720A
	22 V to 220 V		
	10 Hz to 20 Hz	0.024 % + 4 mV	
	20 Hz to 40 Hz	0.009 3 % + 1.5 mV	
	40 Hz to 20 kHz	0.005 6 % + 0.6 mV	
	20 kHz to 50 kHz	0.008 3 % + 1 mV	
	50 kHz to 100 kHz	0.016 % + 2.5 mV	
	100 kHz to 300 kHz	0.09 % + 16 mV	
	300 kHz to 500 kHz	0.44 % + 40 mV	
	500 kHz to 1 MHz	0.8 % + 80 mV	
AC Voltage – Measuring Equipment ¹	220 V to 1 100 V		Fluke 5720A/5725A
	40 Hz to 1 kHz	0.011 % + 4 mV	
	1 kHz to 20 kHz	0.017 % + 6 mV	
	20 kHz to 30 kHz	0.06 % + 11 mV	
	220 V to 750 V		
	30 kHz to 50 kHz	0.061 % + 11 mV	
50 kHz to 100 kHz	0.23 % + 45 mV		
Capacitance – Measuring Equipment ¹	0.19 nF to < 1.1 nF		Fluke 5520A
	10 Hz to 10 kHz	0.39 % + 7.8 pF	
	1.1 nF to < 3.3 nF		
	10 Hz to 3 kHz	0.39 % + 7.8 pF	



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Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Capacitance – Measuring Equipment ¹	3.3 nF to < 11 nF 10 Hz to 1 kHz	0.21 % + 7.8 pF	Fluke 5520A
	11 nF to < 110 nF 10 Hz to 1 kHz	0.21 % + 78 pF	
	110 nF to < 330 nF 10 Hz to 1 kHz	0.21 % + 0.23 nF	
	0.33 μF to < 1.1 μF 10 Hz to 600 Hz	0.21 % + 0.78 nF	
	1.1 μF to < 3.3 μF 10 Hz to 300 Hz	0.21 % + 2.3 nF	
	3.3 μF to < 11 μF 10 Hz to 150 Hz	0.21 % + 7.8 nF	
	11 μF to < 33 μF 10 Hz to 120 Hz	0.32 % + 23 nF	
	33 μF to < 110 μF 10 Hz to 80 Hz	0.36 % + 78 nF	
	110 μF to < 330 μF DC to 50 Hz	0.36 % + 0.23 μF	
	0.33 mF to < 1.1 mF DC to 20 Hz	0.35 % + 0.78 μF	
1.1 mF to < 3.3 mF DC to 6 Hz	0.35 % + 2.3 μF		



Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Capacitance – Measuring Equipment ¹	3.3 mF to < 11 mF DC to 2 Hz	0.35 % + 7.8 μF	Fluke 5520A
	11 mF to < 33 mF DC to 0.6 Hz	0.58 % + 23 μF	
	33 mF to < 110 mF DC to 0.2 Hz	0.85 % + 78 μF	
Electrical Calibration of Thermocouple Devices ¹ Type E	-270 °C to -245 °C	2.1 °C	Ectron 1140A
	-245 °C to -195 °C	2 °C	
	-195 °C to -155 °C	1.1 °C	
	-155 °C to -90 °C	0.93 °C	
	-90 °C to 0 °C	0.08 °C	
	0 °C to 15 °C	0.08 °C	
	15 °C to 890 °C	0.07 °C	
	890 °C to 1 000 °C	0.08 °C	
Type J	-210 °C to -180 °C	0.13 °C	Ectron 1140A
	-180 °C to -120 °C	0.11 °C	
	-120 °C to -50 °C	0.09 °C	
	-50 °C to 990 °C	0.08 °C	
	990 °C to 1 200 °C	0.08 °C	
Type K	-270 °C to -255 °C	2.3 °C	Ectron 1140A
	-255 °C to -195 °C	0.73 °C	
	-195 °C to -115 °C	0.14 °C	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Electrical Calibration of Thermocouple Devices ¹ Type K	-115 °C to -55 °C	0.1 °C	Ectron 1140A
	-55 °C to 1 000 °C	0.08 °C	
	1 000 °C to 1 372 °C	0.09 °C	
Type T	-270 °C to -250 °C	1.8 °C	Ectron 1140A
	-255 °C to -240 °C	0.52 °C	
	-240 °C to -210 °C	0.32 °C	
	-210 °C to -150 °C	0.19 °C	
	-150 °C to -40 °C	0.13 °C	
	-40 °C to 100 °C	0.09 °C	
	100 °C to 400 °C	0.08 °C	
Type R	-50 °C to -30 °C	0.68 °C	
	-30 °C to 45 °C	0.58 °C	
	45 °C to 160 °C	0.42 °C	
	160 °C to 380 °C	0.31 °C	
	380 °C to 775 °C	0.28 °C	
	775 °C to 1 768.1 °C	0.23 °C	
Type S	-50 °C to -30 °C	0.65 °C	
	-30 °C to 45 °C	0.59 °C	
	45 °C to 105 °C	0.42 °C	
	105 °C to 310 °C	0.33 °C	
	310 °C to 615 °C	0.31 °C	
	615 °C to 1 768.1 °C	0.27 °C	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Electrical Calibration of Thermocouple Devices ¹ Type N	-270 °C to -260 °C	5.1 °C	Ectron 1140A
	-260 °C to -200 °C	1.1 °C	
	-200 °C to -140 °C	0.25 °C	
	-140 °C to -70 °C	0.16 °C	
Power – Measuring Equipment DC Power 0.33 mA to 330 mA	11 μW to 1.1 mW	0.024 %	Fluke 5520A
	1.1 mW to 110 mW	0.027 %	Fluke 5520A
	0.11W to 110 W	0.024 %	
	110 W to 330 W	0.018 %	
0.33 A to 3 A	11 W to 110 mW	0.044 %	Fluke 5520A
	0.11 W to 990 W	0.053 %	
	1 W to 3 kW	0.009 6 %	
3 A to 20.5 A	0.099 W to 0.99 W	0.088 %	Fluke 5520A
	0.99 W to 6.8 kW	0.07 %	
	6.8 W to 20.5 kW	0.04 %	
AC Power ⁴ (PF = 1) 3.3 mA to 9 mA	0.11 mW to 3 mW 10 Hz to 65 Hz	0.13 %	Fluke 5520A
	3 mW to 9 W 10 Hz to 65 Hz	0.077 %	
9 mA to 33 mA	0.3 mW to 10 mW 10 Hz to 65 Hz	0.089 %	
	10 mW to 33 W 10 Hz to 65 Hz	0.077 %	
33 mA to 90 mA	1 mW to 30 mW 10 Hz to 65 Hz	0.071 %	Fluke 5520A
	30 mW to 90 W 10 Hz to 65 Hz	0.057 %	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
AC Power ⁴ (PF = 1) 90 mA to 330 mA	3 mW to 100 mW 10 Hz to 65 Hz	0.089 %	Fluke 5520A
	100 mW to 300 W 10 Hz to 65 Hz	0.078 %	
0.33 A to 0.9 A	11 mW to 300 mW 10 Hz to 65 Hz	0.071 %	
	300 mW to 900 W 10 Hz to 65 Hz	0.081 %	
0.9 A to 2.2 A	30 mW to 720 mW 10 Hz to 65 Hz	0.089 %	
	720 mW to 2 kW 10 Hz to 65 Hz	0.079 %	
2.2 A to 4.5 A	80 mW to 1.4 W 10 Hz to 65 Hz	0.088 %	
	1.4 W to 4.5 kW 10 Hz to 65 Hz	0.18 %	
4.5 A to 20.5 A	150 mW to 6.7 W 10 Hz to 65 Hz	0.17 %	
	6.7 W to 20 kW 10 Hz to 65 Hz	0.17 %	
Phase Meters – Measure Equipment ¹	0° to 179.99°		
	10 Hz to 65 Hz	0.11°	
	65 Hz to 500 Hz	0.2°	
	500 Hz to 1 kHz	0.4°	
	1 kHz to 5 kHz	1.9°	
	5 kHz to 10 kHz	3.9°	
	10 kHz to 30 kHz	7.8°	



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Oscilloscopes ¹ Amplitude DC ¹ into 50 Ω Load into 1 MΩ Load	(-6.6 to 6.6) V (-130 to 130) V	0.20% + 31 μV 0.039% + 31 μV	Fluke 5520A/SC1100
Amplitude Square Wave ¹ into 50 Ω Load Rate: 10 Hz to 10 kHz	1 mV _(pk-pk) to 6.6 V _(pk-pk)	0.19% + 31 μV	
into 1 MΩ Load Rate: 10 Hz to 1 kHz Rate: 1 kHz to 10 kHz	1 mV _(pk-pk) to 6.6 V _(pk-pk) 1 mV _(pk-pk) to 6.6 V _(pk-pk)	0.078% + 31 μV 0.19% + 31 μV	
Timing - Generate ¹ 50 Ω Load	5 s 2 s 1 s 500 ms 200 ms 100 ms 50 ms 20 mS to 1 nS	0.30 % 0.12 % 0.062 % 0.032 % 0.014 % 0.007 6 % 0.004 6 % 0.000 22 %	Fluke 5520A/SC1100
Rise Time – Generate ^{1,4} 50 Ω Load 5.0 mV _(pk-pk) to 2.5 V _(pk-pk) Rate: 1 kHz to 2 MHz Rate: 2 MHz to 10 MHz	250 ps (nominal) 250 ps (nominal)	50 ps 50 ps	Fluke 5520A/SC1100



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Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Leveled Sine Wave Generate ¹ 50 Ω Load 5.0 mV _(pk-pk) to 5.5 V _(pk-pk)	50 kHz 50 kHz to 100 MHz 100 MHz to 300 MHz 300 MHz to 600 MHz 5.0 mV _(pk-pk) to 3.5 V _(pk-pk) 600 MHz to 1 GHz	1.8 % + 230 μV 2.8 % + 230 μV 3.2 % + 230 μV 4.0 % + 230 μV 5.5 % + 230 μV	Fluke 5520A/SC1100
Bandwidth/Flatness Measure ¹ 50 Ω (50 kHz Reference) 5.0 mV _(pk-pk) to 5.5 V _(pk-pk)	50 kHz to 100 MHz 100 MHz to 300 MHz 300 MHz to 600 MHz 5.0 mV _(pk-pk) to 3.5 V _(pk-pk) 600 MHz to 1.1 GHz	1.4 % + 78 μV 1.8 % + 78 μV 3.2 % + 78 μV 4.0 % + 78 μV	Fluke 5520A/SC1100
Input Impedance Measure ¹ 50 Ω 1 MΩ	40 Ω to 60 Ω 500 kΩ to 1.5 MΩ	0.082 % 0.081 %	Fluke 5520A/SC1100
Input Capacitance Measure ¹	5 pF to 50 pF	3.9 % + 0.39 pF	Fluke 5520A/SC1100
Wave Generator – Source ¹ Amplitude (10 Hz to 10 kHz) Sine, Square, Triangle 50 Ω Load 1 MΩ Load	1.8 mV _(pk-pk) to 2.5 V _(pk-pk) 1.8 mV _(pk-pk) to 55 V _(pk-pk)	2.3 % + 78 μV _(pk-pk) 2.3 % + 78 μV _(pk-pk)	Fluke 5520A/SC1100



Electrical - DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Wave Generator – Source ¹ Frequency Sine, Square, Triangle	10 Hz to 10 kHz	0.001 9% + 0.012 Hz	Fluke 5520A/SC1100

Length – Dimensional Metrology

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ⁵	Reference Standard, Method and/or Equipment
Micrometers – Outside, Inside, Depth ¹	0.05 in to 0.4 in	27 μin	Comparison to Gage Blocks
	0.4 to 40 in	(10 + 19L) μin	
Calipers – Outside, Inside, Depth ¹	0.05 in to 0.4 in	60 μin	Comparison to Gage Blocks
	0.4 to 40 in	(60 + 19L) μin	
Anvil Flatness ¹	0 in to 1 in	4.7 μin	Optical Flats
Dial Indicators ¹	0.01 in to 0.4 in	7 μin	Gage Blocks with Surface Plate
	0.45 in to 3 in	(17 + 5.3L) μin	
Height Measuring Equipment	0.01 in to 8 in	(17 + 3.4L) μin	Gage Blocks with Surface Plate
	8 in to 40 in	(15 + 4.3L) μin	
Height Measure	0.01 in to 6 in	(24 + 2.6L) μin	Gage Blocks with Surface Plate
	6 in to 12 in	(14 + 4.4L) μin	
Pin Gage – Outer Diameter Non-contact	0.004 in to 1 in	32 μin	Laser Micrometer



Mass and Mass Related

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Force Measuring Equipment – Tension and Compression	1 lbf to 50 lbf	0.013 %	Dead Weight
	50 lbf to 250 lbf	0.004 4 % + 0.006 5 lbf	
	1 gf to 4 kgf	0.013 %	
Torque – Measure ¹	20 ozf·in to 600 lbf·ft	1 %	Torque Calibrator
Balances – Metric ¹	2 kg	1.3 mg	Class S Weights
	1 kg	700 µg	
	500 g	310 µg	
	200 g	180 µg	
Balances – Metric ¹	100 g	83 µg	Class 1 Weights
	50 g	46 µg	
	20 g	29 µg	
	10 g	16 µg	
	5 g	12 µg	
	2 g	7.7 µg	
	1 g	7.7 µg	
	Up to 500 mg	5.8 µg	
Balances – Avoirdupois ¹	1 lb to 400 lb	0.012 %	NIST Class F Weights
Absolute Pressure – Source (Pneumatic)	0 psia to 25 psia	0.001 9 psia	Ruska 7250xi
	25 psia to 500 psia	0.006 5 % + 0.001 psia	
Gage Pressure – Source (Pneumatic) ¹	-15 psig to 25 psig	0.0017 psig	Ruska 7250xi
	25 psig to 500 psig	0.006 5 %	
Gage Pressure – Source (Hydraulic) ¹	0 psig to 1 500 psig	0.36 psi	Fluke RPM4-E-DWT
	1 500 psig to 15 000 psig	0.023 %	



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Mass and Mass Related

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Volume – Pipette ¹	(0.1 to 10) µL	0.026 µL	Gravimetric Method
	(>10 to 20) µL	0.031 µL	
	(>20 to 30) µL	0.051 µL	
	(>30 to 50) µL	0.099 µL	
	(>50 to 100) µL	0.15 µL	
	(>100 to 200) µL	0.19 µL	
	(>200 to 500) µL	0.22 µL	
	(>500 to 1 000) µL	0.25 µL	
	(>1 000 to 1 500) µL	0.35 µL	
	(>1 500 to 2 000) µL	0.46 µL	
	(>2 000 to 2 500) µL	0.52 µL	
	(>2 500 to 3 000) µL	0.63 µL	
	(>3 000 to 5 000) µL	0.99 µL	
	(>5 000 to 10 000) µL	2 µL	
Flow - Gas	(0.001 to 10) slpm	0.23%	Bell Prover
	(>10 to 680) slpm	0.15%	
Flow - Liquid	(0.001 to 60) gpm (0.004 to 230) lpm (0.4 to 23 000) pph	0.1%	Liquid Ballistic Prover

Thermodynamic

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Temperature – Measuring Equipment ¹	0 °C to 100 °C	0.038 °C	Hart 5628 w/Dry Block



Thermodynamic

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Temperature – Measure ¹	-195 °C to 0 °C	0.012 °C	Hart 5628
	0 °C to 420 °C	0.026 °C	
	420 °C to 600 °C	0.036 °C	
Infrared Temperature – Measuring Equipment	-15 °C to 0 °C	0.79 °C	Fluke Black Body
	0 °C to 50 °C	0.54 °C	
	50 °C to 100 °C	0.67 °C	
Infrared Temperature – Measuring Equipment	100 °C to 120 °C	0.75 °C	Fluke Black Body
	120 °C to 200 °C	0.97 °C	
	200 °C to 350 °C	1.7 °C	
	350 °C to 500 °C	2.2 °C	

Time and Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-) ²	Reference Standard, Method and/or Equipment
Frequency – Source and Measure In-Lab	10 MHz	5.8 x 10 ⁻¹⁰ Hz/Hz	SRS FS725
			Field ¹
Total Harmonic Distortion	0.01 % to 100 %		Agilent 339A
	20 Hz to 20 kHz	13 %	
	20 kHz to 50 kHz	21 %	
	50 kHz to 100 kHz	37 %	
	100 kHz to 500 MHz	37 %	Tektronix 2795
Rise Time – Measure	≥ 800 ps	0.13 % + 0.17 ns	Tektronix TDS 510A

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. Values listed with percent (%) are percent of reading or generated value unless otherwise noted.
3. The uncertainties shown are for the most favorable conditions. There is an increase in uncertainty that corresponds to the laboratory's AC voltage and current uncertainties at frequencies other than the ones shown. Power factors (PF) other than the one shown contribute to the power uncertainty. PF is related to the cosine of phase. Therefore, uncertainties track the laboratory's phase uncertainty closely at PF near one, but are magnified heavily as PF approaches zero. The lab may also report reactive power, apparent power, and power factor under this accreditation. If needed, contact laboratory for more information regarding uncertainties at frequency and power factor combinations other than the ones shown.
4. The stated uncertainty is the laboratory's ability to source a fast rise pulse that is approximately 250 ps. In the typical application of measuring rise time of an oscilloscope, this value is one of the contributing factors, but other factors are derived from the DUT.
5. L = Length in inches
6. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-2489.11.



Vice President

